MC10131

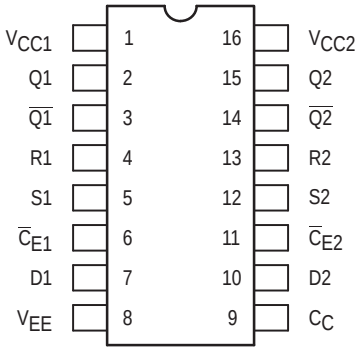
Dual Type D Master-Slave Flip-Flop

The MC10131 is a dual master–slave type D flip–flop. Asynchronous Set (S) and Reset (R) override Clock (C_C) and Clock Enable (C_E) inputs. Each flip–flop may be clocked separately by holding the common clock in the low state and using the enable inputs for the clocking function. If the common clock is to be used to clock the flip–flop, the Clock Enable inputs must be in the low state. In this case, the enable inputs perform the function of controlling the common clock.

The output states of the flip–flop change on the positive transition of the clock. A change in the information present at the data (D) input will not affect the output information at any other time due to master slave construction.

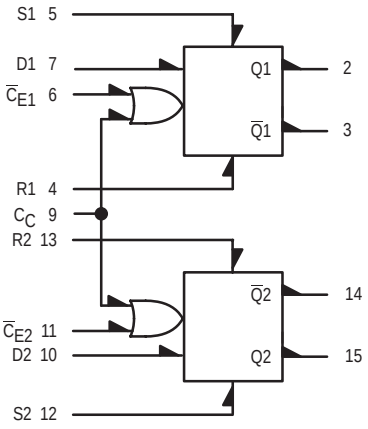
- P_D = 235 mW typ/pkg (No Load)
- F_{Tog} = 160 MHz typ
- t_{pd} = 3.0 ns typ
- t_r, t_f = 2.5 ns typ (20%–80%)

DIP PIN ASSIGNMENT



Pin assignment is for Dual–in–Line Package.
For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).

LOGIC DIAGRAM

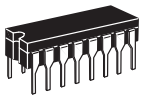


V_{CC1} = PIN 1
V_{CC2} = PIN 16
V_{EE} = PIN 8

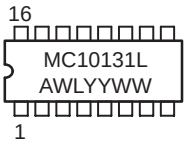
ON Semiconductor

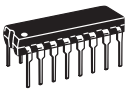
http://onsemi.com

MARKING DIAGRAMS

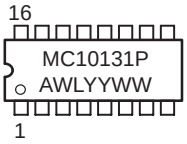


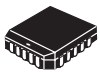
CDIP–16
L SUFFIX
CASE 620



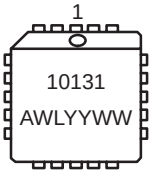


PDIP–16
P SUFFIX
CASE 648





PLCC–20
FN SUFFIX
CASE 775



A = Assembly Location
WL = Wafer Lot
YY = Year
WW = Work Week

CLOCKED TRUTH TABLE

C	D	Q_{n+1}
L	X	Q_n
H	L	L
H	H	H

C = C_E + C_C. A clock H is a clock transition from a low to a high state.

R–S TRUTH TABLE

R	S	Q_{n+1}
L	L	Q_n
L	H	H
H	L	L
H	H	N.D.

N.D. = Not Defined

ORDERING INFORMATION

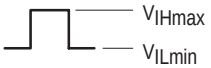
Device	Package	Shipping
MC10131L	CDIP–16	25 Units / Rail
MC10131P	PDIP–16	25 Units / Rail
MC10131FN	PLCC–20	46 Units / Rail

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Pin Under Test	Test Limits							Unit
			–30°C		+25°C			+85°C		
			Min	Max	Min	Typ	Max	Min	Max	
Power Supply Drain Current	I_E	8		62		45	56		62	mAdc
Input Current	I_{inH}	4 5 6 7 9		525 525 350 390 425			330 330 220 245 265		330 330 220 245 265	μAdc
	I_{inL}	4, 5* 6, 7, 9*	0.5 0.5		0.5 0.5			0.3 0.3		μAdc
Output Voltage Logic 1	V_{OH}	2 2†	–1.060 –1.060	–0.890 –0.890	–0.960 –0.960		–0.810 –0.810	–0.890 –0.890	–0.700 –0.700	Vdc
Output Voltage Logic 0	V_{OL}	2 3†	–1.890 –1.890	–1.675 –1.675	–1.850 –1.850		–1.650 –1.650	–1.825 –1.825	–1.615 –1.615	Vdc
Threshold Voltage Logic 1	V_{OHA}	2 2†	–1.080 –1.080		–0.980 –0.980			–0.910 –0.910		Vdc
Threshold Voltage Logic 0	V_{OLA}	2 3†		–1.655 –1.655			–1.630 –1.630		–1.595 –1.595	Vdc
Switching Times (50Ω Load) Clock Input										ns
Propagation Delay	t_{9+2-} t_{9+2+} t_{6+2+} t_{6+2-}	2 2 2 2	1.7 1.7 1.7 1.7	4.6 4.6 4.6 4.6	1.8 1.8 1.8 1.8	3.0 3.0 3.0 3.0	4.5 4.5 4.5 4.5	1.8 1.8 1.8 1.8	5.0 5.0 5.0 5.0	
Rise Time (20 to 80%)	t_{2+}	2	1.0	4.6	1.1	2.5	4.5	1.1	4.9	
Fall Time (20 to 80%)	t_{2-}	2	1.0	4.6	1.1	2.5	4.5	1.1	4.9	
Set Input										ns
Propagation Delay	t_{5+2+} t_{12+15+} t_{5+3-} t_{12+14-}	2 15 3 14	1.7 1.7 1.7 1.7	4.4 4.4 4.4 4.4	1.8 1.8 1.8 1.8	2.8 2.8 2.8 2.8	4.3 4.3 4.3 4.3	1.8 1.8 1.8 1.8	4.8 4.8 4.8 4.8	
Reset Input										ns
Propagation Delay	t_{4+2-} t_{13+15-} t_{4+3-} t_{13+14+}	2 15 3 14	1.7 1.7 1.7 1.7	4.4 4.4 4.4 4.4	1.8 1.8 1.8 1.8	2.8 2.8 2.8 2.8	4.3 4.3 4.3 4.3	1.8 1.8 1.8 1.8	4.8 4.8 4.8 4.8	
Setup Time	t_{setup}	7	2.5		2.5			2.5		ns
Hold Time	t_{hold}	7	1.5		1.5			1.5		ns
Toggle Frequency (Max)	f_{tog}	2	125		125	160		125		MHz

* Individually test each input applying V_{IH} or V_{IL} to input under test.

† Output level to be measured after a clock pulse has been applied to the $\overline{C}_E$ Input (Pin 6)

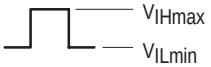


ELECTRICAL CHARACTERISTICS (continued)

				TEST VOLTAGE VALUES (Volts)					
			@ Test Temperature	V_{IHmax}	V_{ILmin}	V_{IHAmin}	V_{ILAmax}	V_{EE}	
			–30°C	–0.890	–1.890	–1.205	–1.500	–5.2	
			+25°C	–0.810	–1.850	–1.105	–1.475	–5.2	
			+85°C	–0.700	–1.825	–1.035	–1.440	–5.2	
Characteristic		Symbol	Pin Under Test	TEST VOLTAGE APPLIED TO PINS LISTED BELOW					(V_{CC}) Gnd
				V_{IHmax}	V_{ILmin}	V_{IHAmin}	V_{ILAmax}	V_{EE}	
Power Supply Drain Current		I_E	8					8	1, 16
Input Current		I_{inH}	4 5 6 7 9	4 5 6 7 9				8 8 8 8 8	1, 16 1, 16 1, 16 1, 16 1, 16
		I_{inL}	4, 5* 6, 7, 9*		* *			8 8	1, 16 1, 16
Output Voltage	Logic 1	V_{OH}	2 2†	5 7				8 8	1, 16 1, 16
Output Voltage	Logic 0	V_{OL}	2 3†	5 7				8 8	1, 16 1, 16
Threshold Voltage	Logic 1	V_{OHA}	2 2†			5 7	 9	8 8	1, 16 1, 16
Threshold Voltage	Logic 0	V_{OLA}	2 3†			5 7	 9	8 8	1, 16 1, 16
Switching Times (50Ω Load) Clock Input				+1.11Vdc		Pulse In	Pulse Out	–3.2 V	+2.0 V
	Propagation Delay	t_{9+2-} t_{9+2+} t_{6+2+} t_{6+2-}	2 2 2 2	 7 7 		9 9 6 6	2 2 2 2	8 8 8 8	1, 16 1, 16 1, 16 1, 16
Rise Time	(20 to 80%)	t_{2+}	2	7		9	2	8	1, 16
Fall Time	(20 to 80%)	t_{2-}	2			9	2	8	1, 16
Set Input									
	Propagation Delay	t_{5+2+} t_{12+15+} t_{5+3-} t_{12+14-}	2 15 3 14	 6 9		5 12 5 12	2 15 3 14	8 8 8 8	1, 16 1, 16 1, 16 1, 16
Reset Input									
	Propagation Delay	t_{4+2-} t_{13+15-} t_{4+3-} t_{13+14+}	2 15 3 14	 6 9		4 13 4 13	2 15 3 14	8 8 8 8	1, 16 1, 16 1, 16 1, 16
Setup Time		t_{setup}	7			6, 7	2	8	1, 16
Hold Time		t_{hold}	7			6, 7	2	8	1, 16
Toggle Frequency (Max)		f_{tog}	2			6	2	8	1, 16

* Individually test each input applying V_{IH} or V_{IL} to input under test.

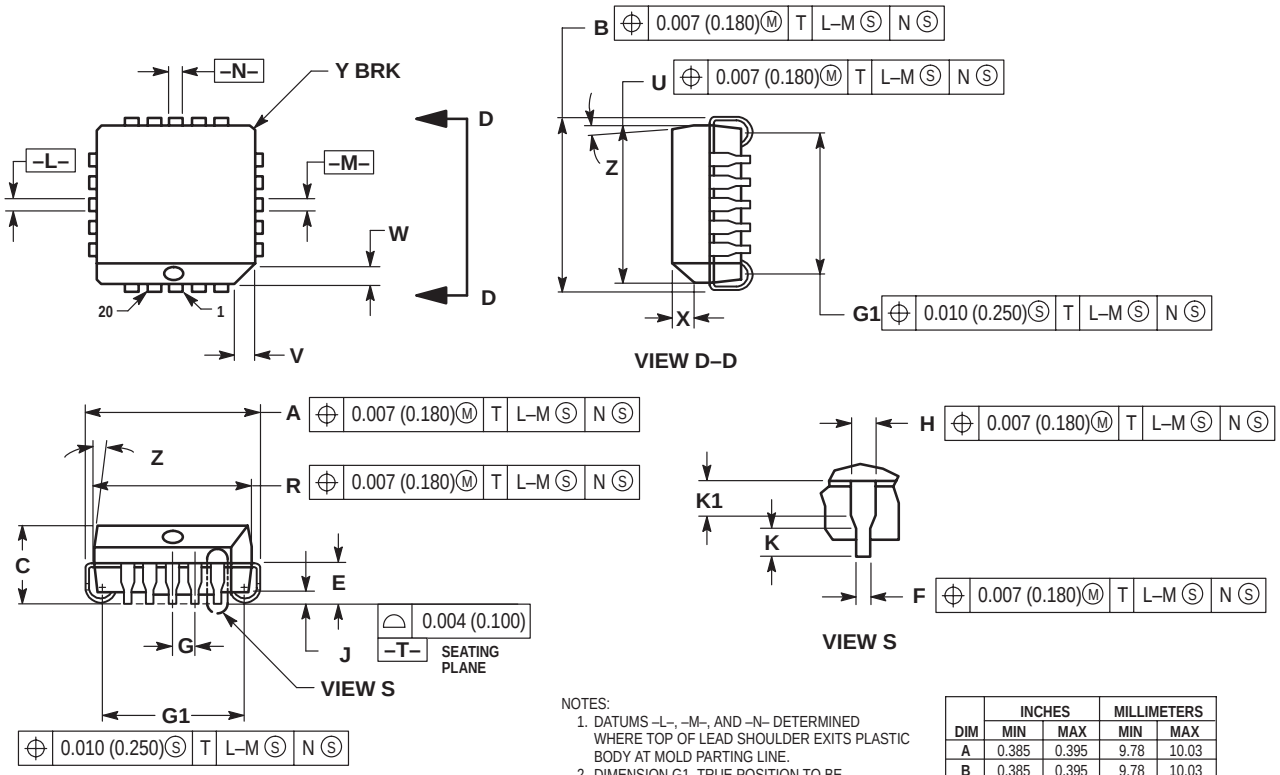
† Output level to be measured after a clock pulse has been applied to the $\overline{C}_E$ Input (Pin 6)



Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50–ohm resistor to –2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

PACKAGE DIMENSIONS

PLCC–20
FN SUFFIX
PLASTIC PLCC PACKAGE
CASE 775–02
ISSUE C

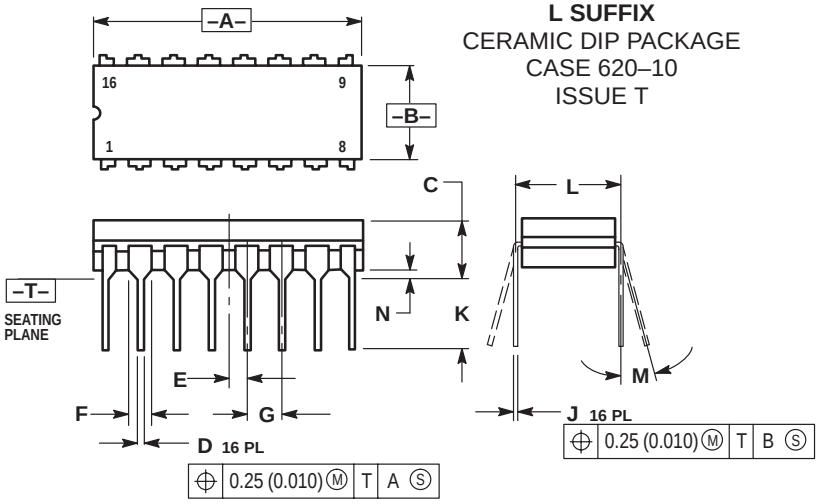


NOTES:
1. DATUMS –L–, –M–, AND –N– DETERMINED WHERE TOP OF LEAD SHOULDER EXITS PLASTIC BODY AT MOLD PARTING LINE.
2. DIMENSION G1, TRUE POSITION TO BE MEASURED AT DATUM –T–, SEATING PLANE.
3. DIMENSIONS R AND U DO NOT INCLUDE MOLD FLASH. ALLOWABLE MOLD FLASH IS 0.010 (0.250) PER SIDE.
4. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
5. CONTROLLING DIMENSION: INCH.
6. THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM BY UP TO 0.012 (0.300). DIMENSIONS R AND U ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.
7. DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940). THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025 (0.635).

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.385	0.395	9.78	10.03
B	0.385	0.395	9.78	10.03
C	0.165	0.180	4.20	4.57
E	0.090	0.110	2.29	2.79
F	0.013	0.019	0.33	0.48
G	0.050 BSC		1.27 BSC	
H	0.026	0.032	0.66	0.81
J	0.020	—	0.51	—
K	0.025	—	0.64	—
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
V	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
X	0.042	0.056	1.07	1.42
Y	—	0.020	—	0.50
Z	2 °	10 °	2 °	10 °
G1	0.310	0.330	7.88	8.38
K1	0.040	—	1.02	—

PACKAGE DIMENSIONS

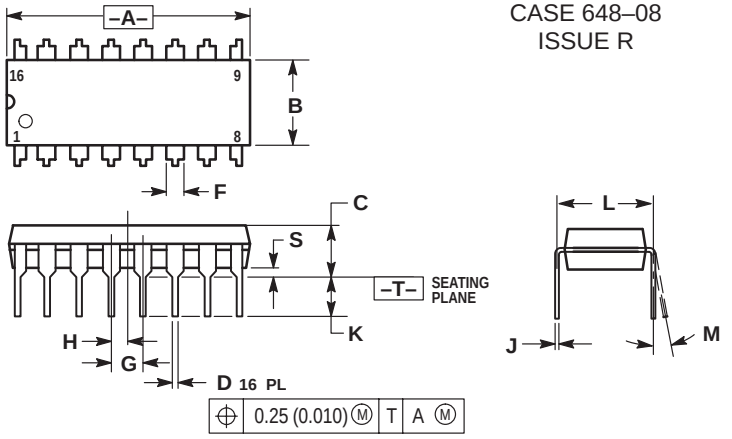
CDIP–16
L SUFFIX
CERAMIC DIP PACKAGE
CASE 620–10
ISSUE T



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSION L TO CENTER OF LEAD WHEN FORMED PARALLEL.
4. DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC BODY.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.750	0.785	19.05	19.93
B	0.240	0.295	6.10	7.49
C	—	0.200	—	5.08
D	0.015	0.020	0.39	0.50
E	0.050 BSC		1.27 BSC	
F	0.055	0.065	1.40	1.65
G	0.100 BSC		2.54 BSC	
H	0.008	0.015	0.21	0.38
K	0.125	0.170	3.18	4.31
L	0.300 BSC		7.62 BSC	
M	0 °	15 °	0 °	15 °
N	0.020	0.040	0.51	1.01

PDIP–16
P SUFFIX
PLASTIC DIP PACKAGE
CASE 648–08
ISSUE R



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
5. ROUNDED CORNERS OPTIONAL.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.740	0.770	18.80	19.55
B	0.250	0.270	6.35	6.85
C	0.145	0.175	3.69	4.44
D	0.015	0.021	0.39	0.53
F	0.040	0.70	1.02	1.77
G	0.100 BSC		2.54 BSC	
H	0.050 BSC		1.27 BSC	
J	0.008	0.015	0.21	0.38
K	0.110	0.130	2.80	3.30
L	0.295	0.305	7.50	7.74
M	0 °	10 °	0 °	10 °
S	0.020	0.040	0.51	1.01

Notes

Notes

PUBLICATION ORDERING INFORMATION

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